

Amendments to the Claims

This listing of claims will replace all prior versions and listings of claims in the application.

Listing of Claims

1. (Currently amended) An inspection or review system, comprising:

an optical component configured to project ultraviolet light onto a specimen during inspection or review of the specimen, wherein the specimen is a wafer or a reticle; and

a liquid disposed between the optical component and the specimen during the inspection or the review, wherein the liquid is in contact with a surface of the optical component and a surface of the specimen, and wherein the liquid does not permanently alter properties of the optical component or properties of the specimen.

2. (Previously presented) The system of claim 1, wherein the presence of the liquid between the optical component and the specimen increases resolution of the inspection or review system.

3. (Previously presented) The system of claim 1, wherein the liquid has an index of refraction that is approximately equal to an index of refraction of the optical component.

4. (Previously presented) The system of claim 1, wherein the liquid has an index of refraction that is different than an index of refraction of an upper layer formed on the specimen.

5. (Previously presented) The system of claim 1, wherein the liquid occupies approximately an entire volume between the surfaces of the optical component and the specimen.

6. (Previously presented) The system of claim 1, wherein the liquid occupies spaces between features on the specimen.

7. (Previously presented) The system of claim 1, wherein air is not present between the surfaces of the optical component and the specimen.

8. (Currently amended) The system of claim 1, wherein the liquid does not scatter the ultraviolet light.

9. (Previously presented) The system of claim 1, wherein the liquid comprises water.

10. (Previously presented) The system of claim 1, wherein a substantial portion of the liquid comprises water.

11. (Previously presented) The system of claim 1, wherein the liquid comprises a wetting agent.

12. (Previously presented) The system of claim 1, wherein the liquid can be removed from the surface of the specimen after inspection such that a residue is not present on the specimen after the inspection.

13. (Previously presented) The system of claim 1, wherein the inspection or review comprises bright field inspection or review, dark field inspection or review, or dark field and bright field inspection or review.

14. (Previously presented) The system of claim 1, wherein the system is configured as a confocal optical system.

15. (Previously presented) The system of claim 1, wherein the system is configured to scan the specimen while the liquid is disposed between the surfaces of the optical component and the specimen.

16. (Previously presented) The system of claim 1, wherein the system is configured to generate flow of the liquid between the surfaces of the optical component and the specimen during the inspection or review.

17. (Currently amended) An inspection or review system, comprising:

an inspection or review subsystem configured to project ultraviolet light through an optical component, a liquid, and onto a specimen, wherein the liquid contacts the

optical component and the specimen, and wherein the specimen is a wafer or a reticle; and

a processing subsystem configured to remove the liquid from the specimen after inspection or review.

18. (Previously presented) The system of claim 17, wherein the processing subsystem is further configured to clean the specimen after the inspection or review.

19. (Previously presented) The system of claim 17, wherein the processing subsystem is further configured to remove substantially all of the liquid from the specimen.

20. (Previously presented) The system of claim 17, further comprising a handler configured to transfer the specimen from the inspection or review subsystem to the processing subsystem.